Docket No.: 300.1126 Serial No. 10/661,530

IN THE CLAIMS:

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The text of all pending claims, (including withdrawn claims) is set forth below. Cancelled and not entered claims are indicated with claim number and status only. The claims as listed below show added text with <u>underlining</u> and deleted text with <u>strikethrough</u>. The status of each claim is indicated with one of (original), (currently amended), (cancelled), (withdrawn), (new), (previously presented), or (not entered).

Please AMEND claims 1, 2 and 13 in accordance with the following:

1. (CURRENTLY AMENDED) A method for producing a wiring substrate provided with bumps protruding from a surface of the substrate, the method comprising: the steps of:

covering one side of a metallic base with an electrical insulating film and forming open holes in the insulating film so as to expose, at the bottoms thereof, the base,:

etching the base using the insulating film, having the open holes formed therein as a mask, to form concavities in the base,;

electroplating the interior face of each of the concavities, using the base as a plating power supply layer, with a first material to form a barrier metal film on the interior face of each of the concavities—:

filling the concavities with a <u>second, bump</u> material for the bump by electroplating, using the base as a plating power supply layer.

forming a barrier layer of a third material on the surface of the <u>bump</u> material for the <u>bump</u> mater

forming a stack of a predetermined number of wiring patterns on the insulating film, the adjacent wiring patterns in the stack being separated from each other by an intervening insulating layer and being <u>electrically</u> connected to each other through vias formed in the intervening insulating layer, and the wiring patterns being electrically connected to the <u>bump</u> material-for the <u>bump</u> filled-in the concavities, and

removing the base from the stack of wiring patterns having bumps, each <u>bump</u> having the barrier metal film <u>thereon</u>, and removing the barrier metal film from each of the bumps.

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2. (CURRENTLY AMENDED) The method of claim 1, wherein a large-sized metallic foil is used as the base, for of a size permitting simultaneous production of a plurality of wiring substrates.

- 3. (CURRENTLY AMENDED) The method of claim 21, wherein two metallic bases laminated by joining them by adhering the peripheries thereof are used, and the opposed sides of the laminate are covered with the electrical insulating film.
- 4. (ORIGINAL) The method of claim 1, wherein the open holes are formed in the insulating film so as to have tapered interior faces providing a larger diameter at the opening side rather than at the bottom exposing the base.
- 5. (ORIGINAL) The method of claim 1, wherein the etching used to etch the base for the formation of the concavities is isotropic, and wherein each of the concavities is formed to have a diameter at the interface with the insulating film, which is larger than the bottom diameter of the hole provided in the insulating film.
- 6. (ORIGINAL) The method of claim 1, wherein the concavities are filled with the material for the bump in such a manner that the material fully fills the concavity, and partially protrudes into the open hole in the insulating film.
 - 7. (ORIGINAL) The method of claim 1, wherein the base is made of copper.
 - 8. (ORIGINAL) The method of claim 7, wherein the base is a foil of copper.
 - 9. (ORIGINAL) The method of claim 1, wherein the base is removed by etching.
 - 10. (ORIGINAL) The method of claim 1, wherein the bumps are formed of solder or

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gold.

11. (ORIGINAL) The method of claim 9, wherein the bumps are formed of solder.

- 12. (ORIGINAL) The method of claim 1, wherein the barrier metal film is formed of nickel or cobalt.
- 13. (CURRENTLY AMENDED) The method of claim 1, wherein the barrier layer, on the surface of the <u>bump</u> material for <u>bump</u> filled in each concavity, is formed of nickel.